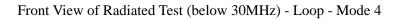
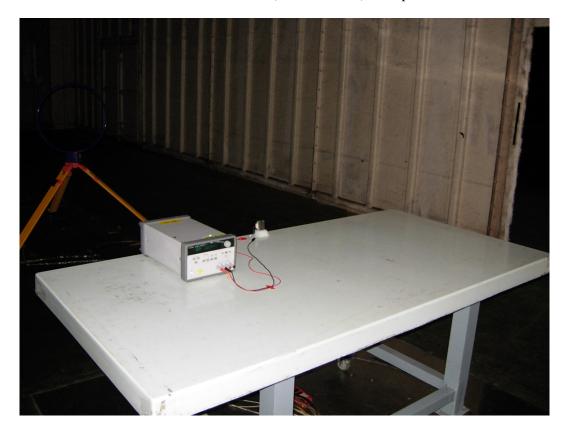


Back View of Radiated Test (below 30MHz) - Loop - Mode 3









Back View of Radiated Test (below 30MHz) - Loop - Mode 4



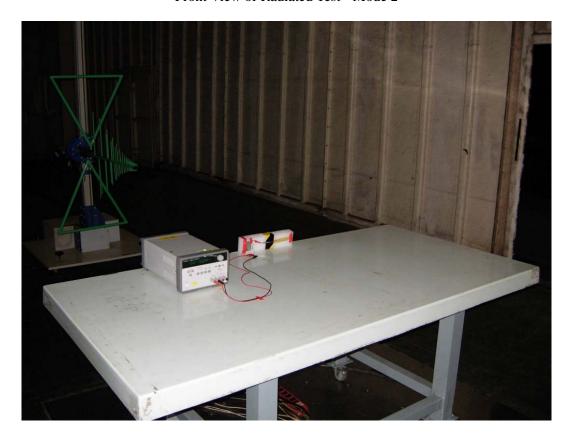




Back View of Radiated Test - Mode 1







Back View of Radiated Test - Mode 2



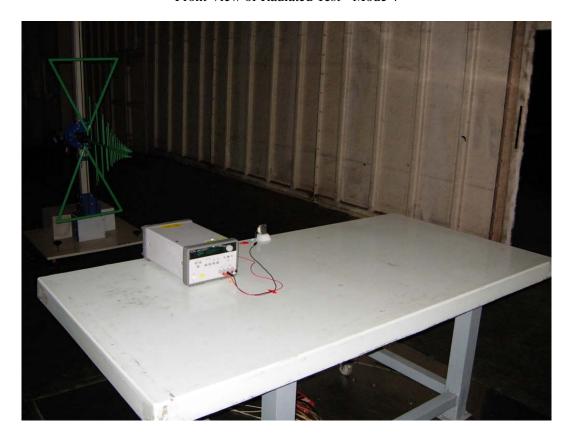




Back View of Radiated Test - Mode 3







Back View of Radiated Test - Mode 4

